



National Accreditation Board for
Testing and Calibration Laboratories

CERTIFICATE OF ACCREDITATION

BNN COMMUNICATION ENGINEERS PVT.LTD. (EMR DIV)

has been assessed and accredited in accordance with the standard

ISO/IEC 17025:2017

**"General Requirements for the Competence of Testing &
Calibration Laboratories"**

for its facilities at

33/33, INDUSTRIAL AREA, SITE 2, LONI ROAD, MOHAN NAGAR, SAHIBABAD, GHAZIABAD, UTTAR
PRADESH, INDIA

in the field of

TESTING

Certificate Number: TC-8196

Issue Date: 08/09/2022

Valid Until:

07/09/2024

This certificate remains valid for the Scope of Accreditation as specified in the annexure subject to continued satisfactory compliance to the above standard & the relevant requirements of NABL.
(To see the scope of accreditation of this laboratory, you may also visit NABL website www.nabl-india.org)

Name of Legal Identity : BNN COMMUNICATION ENGINEERS PRIVATE LIMITED

Signed for and on behalf of NABL



N. Venkateswaran
Chief Executive Officer



National Accreditation Board for Testing and Calibration Laboratories

SCOPE OF ACCREDITATION

Laboratory Name :	BNN COMMUNICATION ENGINEERS PVT.LTD. (EMR DIV), 33/33, INDUSTRIAL AREA, SITE 2, LONI ROAD, MOHAN NAGAR, SAHIBABAD, GHAZIABAD, UTTAR PRADESH, INDIA		
Accreditation Standard	ISO/IEC 17025:2017		
Certificate Number	TC-8196	Page No	1 of 1
Validity	08/09/2022 to 07/09/2024	Last Amended on	29/10/2022

S.No	Discipline / Group	Materials or Products tested	Component, parameter or characteristic tested / Specific Test Performed / Tests or type of tests performed	Test Method Specification against which tests are performed and / or the techniques / equipment used
Site Facility				
1	ELECTRONICS- EMC TEST FACILITY	Fully Anechoic Chamber/Semi Anechoic Chamber / Open Area Test Site	Field Uniformity	IEC 61000-4-3
2	ELECTRONICS- EMC TEST FACILITY	Fully Anechoic Chamber/Semi Anechoic Chamber / Open Area Test Site	Site Voltage Standing Wave Ratio (sVSWR)	CISPR 16-1-4:2019 +AMD1
3	ELECTRONICS- EMC TEST FACILITY	Semi Anechoic Chamber / Open Area Test Site with ground Plane	Normalised Site Attenuation	ANSI C63.4
4	ELECTRONICS- EMC TEST FACILITY	Semi Anechoic Chamber / Open Area Test Site with ground Plane	Normalised Site Attenuation	ANSI C63.4a (Amendment)
5	ELECTRONICS- EMC TEST FACILITY	Semi Anechoic Chamber / Open Area Test Site with ground Plane	Normalised Site Attenuation	CISPR 16-1-4:2019 +AMD1
6	ELECTRONICS- EMC TEST FACILITY	Semi Anechoic Chamber with Ground Plane/Open Area Test Site	ALSE performance validation using Long Wire Antenna Method	IEC/CISPR 25 (Annexure I)
7	ELECTRONICS- EMC TEST FACILITY	Shielded Chamber/ Enclosure/ Room	Shielding Effectiveness	IEEE 299
8	ELECTRONICS- EMC TEST FACILITY	Shielded Chamber/ Enclosure/ Room	Shielding Effectiveness	MIL STD 188-125.1 (Appendix A)
9	ELECTRONICS- EMC TEST FACILITY	Shielded Chamber/ Enclosure/ Room	Shielding Effectiveness	MIL STD 188-125.2, (Appendix A)
10	ELECTRONICS- EMC TEST FACILITY	Shielded Enclosure/Cabinet	Shielding Effectiveness	IEC 61000-5-7
11	ELECTRONICS- EMC TEST FACILITY	Shielded Enclosure/Cabinet (0.75 m to 2 m)	Shielding Effectiveness	IEEE 299.1